INTEGRATED CIRCUITS

DATA SHEET

74ABT833

Octal transceiver with parity generator/checker (3-State)

Product data Supersedes data of 1993 Jun 21





Octal transceiver with parity generator/checker (3-State)

74ABT833

FEATURES

- Low static and dynamic power dissipation with high speed and high output drive
- Open-collector ERROR output with flag register
- Output capability: +64 mA / -32 mA
- Latch-up protection exceeds 500 mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power-up/down 3-State
- Live insertion/extraction permitted

DESCRIPTION

The 74ABT833 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT833 is an octal transceiver with a parity generator/checker and is intended for bus-oriented applications.

When Output Enable A (\overline{OEA}) is HIGH, it will place the A outputs in a high impedance state. Output Enable B (\overline{OEB}) controls the B outputs in the same way.

The parity generator creates an odd parity output (PARITY) when $\overline{\text{OEB}}$ is LOW. When $\overline{\text{OEA}}$ is LOW, the parity of the B port, including the PARITY input, is checked for odd parity. When an error is detected, the error data is sent to the input of a storage register. If a LOW-to-HIGH transition happens at the clock input (CP), the error data is stored in the register and the Open-collector error flag ($\overline{\text{ERROR}}$) will go LOW. The error flag register is cleared with a LOW pulse on the $\overline{\text{CLEAR}}$ input.

If both $\overline{\text{OEA}}$ and $\overline{\text{OEB}}$ are LOW, data will flow from the A bus to the B bus and the part is forced into an error condition which creates an inverted PARITY output. This error condition can be used by the designer for system diagnostics.

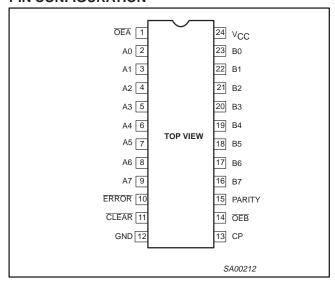
QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25 \text{ °C; GND} = 0 \text{ V}$	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	$C_L = 50 \text{ pF}; V_{CC} = 5 \text{ V}$	3.4	ns
t _{PLH} t _{PHL}	Propagation delay An to PARITY	$C_L = 50 \text{ pF}; V_{CC} = 5 \text{ V}$	7.4	ns
C _{IN}	Input capacitance	$V_I = 0 \text{ V or } V_{CC}$	4	pF
C _{I/O}	I/O capacitance	Outputs disabled; $V_O = 0 \text{ V or } V_{CC}$	7	pF
I _{CCZ}	Total supply current	Outputs disabled; V _{CC} = 5.5 V	50	μΑ

ORDERING INFORMATION

<u> </u>					
PACKAGES	TEMPERATURE RANGE	PART NUMBER	DWG NUMBER		
24-Pin plastic SO	−40 °C to +85 °C	74ABT833D	SOT137-1		
24-Pin Plastic SSOP Type II	−40 °C to +85 °C	74ABT833DB	SOT340-1		
24-Pin Plastic TSSOP Type I	-40 °C to +85 °C	74ABT833PW	SOT355-1		

PIN CONFIGURATION



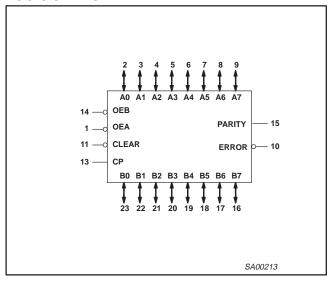
PIN DESCRIPTION

SYMBOL	PIN NUMBER	NAME AND FUNCTION				
A0 – A7	2, 3, 4, 5, 6, 7, 8, 9	A port 3-State inputs/outputs				
B0 – B7	23, 22, 21, 20, 19, 18, 17, 16	B port 3-State inputs/outputs				
OEA	1	Enables the A outputs when LOW				
OEB	14	Enables the B outputs when LOW				
PARITY	15	Parity output/input				
ERROR	10	Error output (open collector)				
CLEAR	11	Clears the error flag register when LOW				
CP	13	Clock input				
GND	12	Ground (0 V)				
V _{CC}	24	Positive supply voltage				

Octal transceiver with parity generator/checker (3-State)

74ABT833

LOGIC SYMBOL



FUNCTION TABLE

			INPUTS		OUTPUTS			
MODE	OEB	OEA	An Σ of Highs	Bn + Parity Σ of Highs	An	Bn	PARITY	
A data to B bus and generate odd parity output	L	Н	Odd Even	(output)	(input)	An	L H	
B data to A bus and check for parity error ¹	Н	L	(output)	Х	Bn	(input)	(input)	
A bus and B bus disabled ²	Н	Н	Х	Х	Z	Z	Z	
A data to B bus and generate inverted parity output	L	L	Odd Even	(output)	(input)	An	H L	

NOTES:

- 1. Error checking is detailed in the Error Flag Function Table below.
- 2. When clocked, the error output is LOW if the sum of A inputs is even or HIGH if the sum of A inputs is odd.

ERROR FLAG FUNCTION TABLE

		INPUT	S	Internal node	Output	
MODE	CLEAR	СР	Bn + Parity Σ of Highs	Point "P"	Pre-state ERRORn-1	ERROR OUTPUT
	Н	1	Odd	Н	Н	Н
Sample	ole H		Even	L	X	L
	Н	Х	X	X	L	L
Hold	Н	1	X	X	Х	NC
Clear	L	Х	X	X X		Н

= HIGH voltage level steady state

LOW voltage level steady state

X = Don't care NC = No change

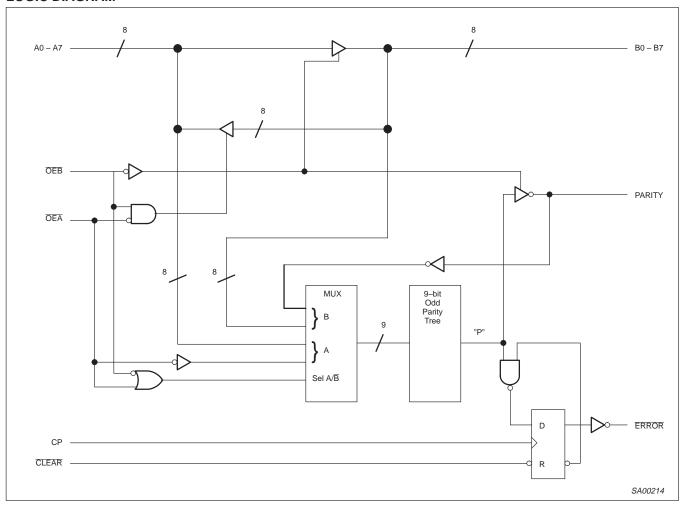
High impedance "off" stateLOW-to-HIGH clock transition

= Not a LOW-to-HIGH clock transition

Octal transceiver with parity generator/checker (3-State)

74ABT833

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V _I < 0 V	-18	mA
VI	DC input voltage ³		−1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0 V	-50	mA
V _{OUT}	DC output voltage ³	output in Off or HIGH state	-0.5 to +5.5	V
l _{out}	DC output current	output in LOW state	128	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

- 1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- 2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

Octal transceiver with parity generator/checker (3-State)

74ABT833

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	ITS	UNIT
		Min	Max	
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	HIGH-level input voltage	2.0		V
V _{IL}	LOW-level input voltage		0.8	V
V _{OH}	HIGH-level output voltage, ERROR		5.5	V
I _{OH}	HIGH-level output current		-32	mA
I _{OL}	LOW-level output current		64	mA
Δt/Δν	Input transition rise or fall rate	0	5	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

						LIMITS			
SYMBOL	PARAM	IETER	TEST CONDITIONS	T _{an}	_{nb} = +25	°C	T _{amb} =	–40 °C 35 °C	UNIT
				Min	Тур	Max	Min	Max	
V _{IK}	Input clamp vol	tage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$		-0.9	-1.2		-1.2	V
I _{OH}	HIGH-level output current ERROR ONLY		$V_{CC} = 5.5 \text{ V}; V_{OH} = 5.5 \text{ V}; V_{I} = V_{IL} \text{ or } V_{IH}$			20		20	μА
			$V_{CC} = 4.5 \text{ V}; I_{OH} = -3 \text{ mA}; V_I = V_{IL} \text{ or } V_{IH}$	2.5	3.5		2.5		V
V _{OH}	HIGH-level output voltage All outputs except ERROR		$V_{CC} = 5.0 \text{ V}; I_{OH} = -3 \text{ mA}; V_I = V_{IL} \text{ or } V_{IH}$	3.0	4.0		3.0		V
			$V_{CC} = 4.5 \text{ V}; I_{OH} = -32 \text{ mA}; V_I = V_{IL} \text{ or } V_{IH}$	2.0	2.6		2.0		V
V _{OL}	LOW-level output voltage		$V_{CC} = 4.5 \text{ V}; I_{OL} = 64 \text{ mA}; V_I = V_{IL} \text{ or } V_{IH}$		0.42	0.55		0.55	V
l _l	Input leakage Control pins current Data pins		V _{CC} = 5.5 V; V _I = GND or 5.5 V		±0.01	±1.0		±1.0	μΑ
			V _{CC} = 5.5 V; V _I = GND or 5.5 V		±5	±100		±100	μΑ
l _{OFF}	Power-off leaka	age current	$V_{CC} = 0.0 \text{ V}; V_{I} \text{ or } V_{O} \le 4.5 \text{ V}$		±5.0	±100		±100	V
I _{PU} I _{PD}	Power-up/dowr output current ³	n 3-State	$V_{\underline{CC}}$ = 2.0 V; or V_{O} = 0.5 V; V_{I} = GND or $V_{\underline{CC}}$; V_{OE} = Don't care		±5.0	±50		±50	V
I _{IH} + I _{OZH}	3-State output l	HIGH current	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.7 \text{ V}; V_{I} = V_{IL} \text{ or } V_{IH}$		5.0	50		50	μΑ
I _{IL} + I _{OZL}	3-State output l	LOW current	$V_{CC} = 5.5 \text{ V}; V_{O} = 0.5 \text{ V}; V_{I} = V_{IL} \text{ or } V_{IH}$		-5.0	-50		-50	μΑ
I _{CEX}	Output High lea	akage current	$V_{CC} = 5.5 \text{ V}; V_{O} = 5.5 \text{ V}; V_{I} = \text{GND or } V_{CC}$		5.0	50		50	μΑ
I _O	Output current ¹		$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	-50	-80	-180	-50	-180	mA
I _{CCH}		<u> </u>	$V_{CC} = 5.5 \text{ V}$; Outputs HIGH, $V_I = \text{GND}$ or V_{CC}		50	250		250	μΑ
I _{CCL}	Quiescent supp	oly current	$V_{CC} = 5.5 \text{ V}$; Outputs LOW, $V_I = \text{GND or } V_{CC}$		20	30		30	mA
I _{CCZ}			$V_{CC} = 5.5 \text{ V}$; Outputs 3-State; $V_I = \text{GND or } V_{CC}$		50	250		250	μΑ
Δl _{CC}	Additional suppinput pin ²	oly current per	V_{CC} = 5.5 V; one input at 3.4 V, other inputs at V_{CC} or GND		0.3	1.5		1.5	mA

NOTES:

- 1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- This is the increase in supply current for each input at 3.4 V.
 This parameter is valid for any V_{CC} between 0 V and 2.1 V, with a transition time of up to 10 msec. From V_{CC} = 2.1 V to V_{CC} = 5 V ± 10%, a transition of up to 100 μsec is permitted. The ERROR output pin 10 is not included in this spec due to the open collector design.

Octal transceiver with parity generator/checker (3-State)

74ABT833

AC CHARACTERISTICS

GND = 0 V; t_{R} = t_{F} = 2.5 ns; C_{L} = 50 pF, R_{L} = 500 Ω

					LIMIT	S		
SYMBOL	PARAMETER	WAVEFORMS	T,	_{amb} = +25 ° ' _{CC} = +5.0 \	C /	T _{amb} = -40 V _{CC} = +5	°C to +85 °C .0 V ±10%	UNIT
			Min	Тур	Max	Min	Max	
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	2	1.2 1.0	3.4 2.6	4.8 4.0	1.2 1.0	5.3 4.5	ns
t _{PLH} t _{PHL}	Propagation delay An to PARITY	1 2	2.1 2.5	7.4 7.4	9.5 9.7	2.1 2.5	11.2 11.0	ns
t _{PLH} t _{PHL}	Propagation delay OEA to PARITY	1 2	2.6 3.1	6.6 6.7	8.5 8.6	2.6 3.1	10.5 10.0	ns
t _{PLH}	Propagation delay CLEAR to ERROR	5	1.0	2.9	4.4	1.0	5.2	ns
t _{PHL}	Propagation delay CP to ERROR	1	2.5	4.2	5.7	2.5	6.2	ns
t _{PZH} t _{PZL}	Output enable time OEA to An or OEB to Bn, PARITY	3 4	1.0 2.1	3.2 4.1	5.1 5.8	1.0 2.1	6.2 6.7	ns
t _{PHZ} t _{PLZ}	Output disable time OEA to An or OEB to Bn, PARITY	3 4	3.1 3.2	5.1 5.6	7.3 7.7	3.1 3.2	7.9 8.1	ns

AC SET-UP REQUIREMENTS

GND = 0 V; t_{R} = t_{F} = 2.5 ns; C_{L} = 50 pF, R_{L} = 500 Ω

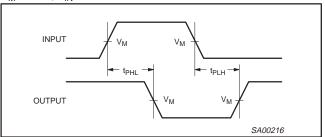
			LIMITS						
SYMBOL	PARAMETER	WAVEFORMS	T _{amb} = V _{CC} =	: +25 °C : +5.0 V	T _{amb} = -40 °C to +85 °C V _{CC} = +5.0 V ±10%	UNIT			
			Min	Тур	Min				
t _s (H) t _s (L)	Set-up time, High or Low Bn or PARITY to CP	6	9.8 8.1	6.9 4.0	9.8 8.1	ns			
t _h (H) t _h (L)	Hold time, High or Low Bn or PARITY to CP	6	0.0 0.0	-3.7 -6.7	0.0 0.0	ns			
t _w (H) t _w (L)	Pulse width, High or Low CP	6	3.0 3.0	1.5 1.0	3.0 3.0	ns			
t _w (L)	Pulse width, Low CLEAR	5	3.0	1.0	3.0	ns			
t _{rec}	Recovery time CLEAR to CP	5	2.0	-0.3	2.0	ns			

Octal transceiver with parity generator/checker (3-State)

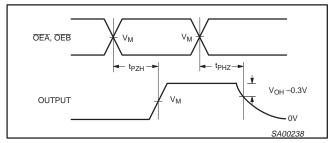
74ABT833

AC WAVEFORMS

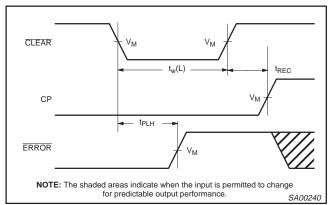
 $V_M = 1.5 \text{ V}, V_{IN} = \text{GND to } 3.0 \text{ V}$



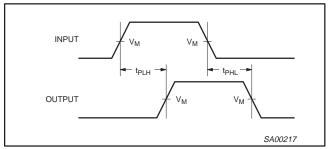
Waveform 1. Propagation Delay for Inverting Output



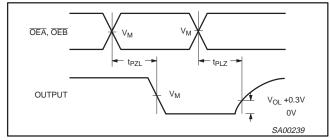
Waveform 3. 3-State Output Enable Time to HIGH Level and Output Disable Time from HIGH Level



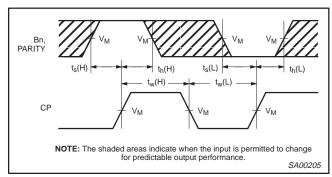
Waveform 5. CLEAR Pulse Width, CLEAR to ERROR Delay and CLEAR to Clock Recovery Time



Waveform 2. Propagation Delay for Non-Inverting Output



Waveform 4. 3-State Output Enable Time to LOW Level and Output Disable Time from LOW Level

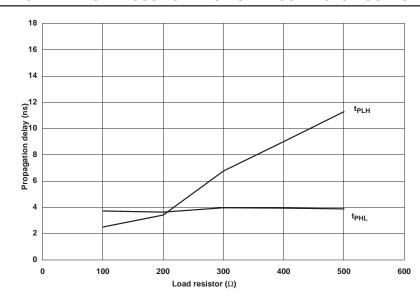


Waveform 6. Data Set-up and Hold Times and Clock Pulse Width

Octal transceiver with parity generator/checker (3-State)

74ABT833

TYPICAL PROPAGATION DELAYS VERSUS LOAD FOR OPEN COLLECTOR OUTPUTS

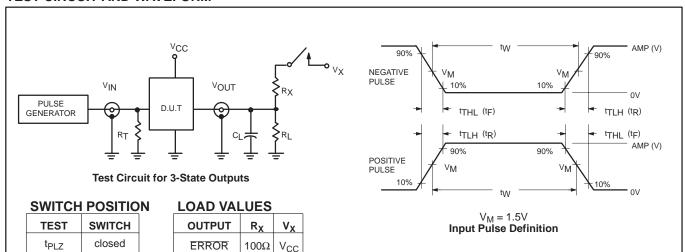


NOTE:

When using Open-Collector parts, the value of the pull–up resistor greatly affects the value of the t_{PLH} . For example, changing the specified pull-up resistor value from 500 Ω to 100 Ω will improve the t_{PLH} over 300% with only a slight change in the t_{PHL} . However, if the value of the pull-up resistor is changed, the user must make certain that the total I_{OL} current through the resistor and the total I_{IL} 's of the receivers does not exceed the I_{OL} maximum specification.

SA00241

TEST CIRCUIT AND WAVEFORM



All other open

DEFINITIONS

 t_{PZL}

closed

R_L = Load resistor; see AC CHARACTERISTICS for value.

All other

 500Ω

7.0V

- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

FAMILY	IN	INPUT PULSE REQUIREMENTS										
FAIVILY	Amplitude	Rep. Rate	t _W	t _R	t _F							
74ABT	3.0V	1MHz	500ns	2.5ns	2.5ns							

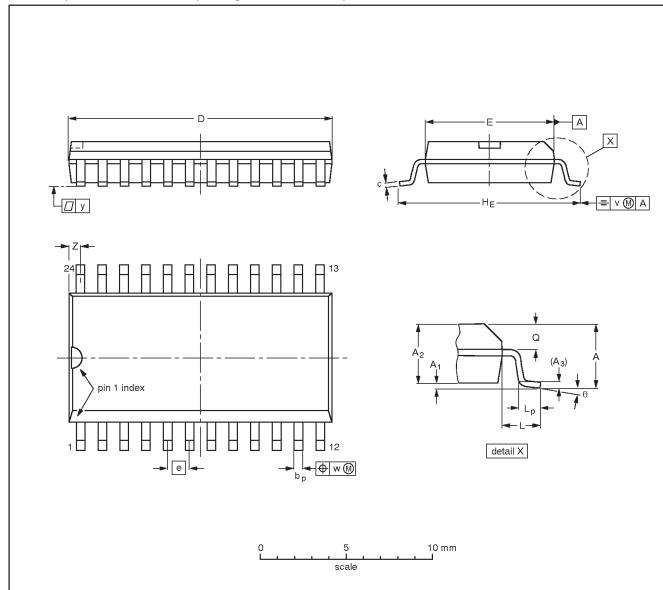
SA00242

Octal transceiver with parity generator/checker (3-State)

74ABT833

SO24: plastic small outline package; 24 leads; body width 7.5 mm

SOT137-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	15.6 15.2	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8°
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.61 0.60	0.30 0.29	0.050	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	o°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

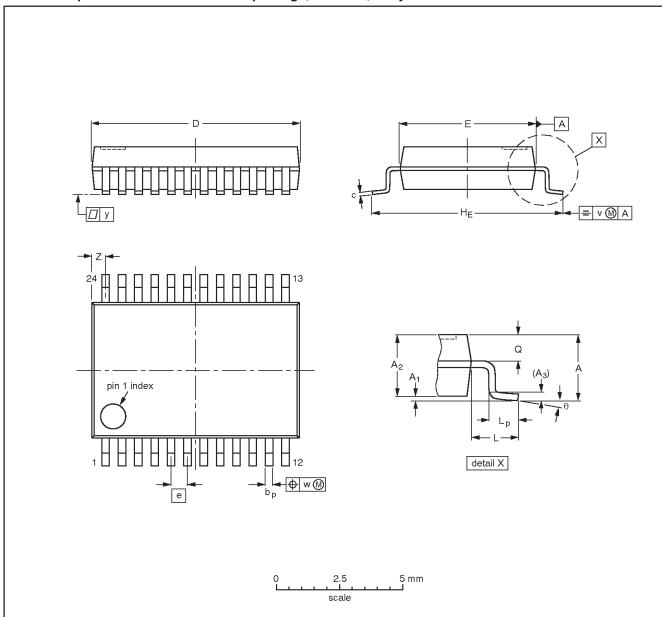
OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT137-1	075E05	MS-013				-97-05-22 99-12-27	

Octal transceiver with parity generator/checker (3-State)

74ABT833

SSOP24: plastic shrink small outline package; 24 leads; body width 5.3 mm

SOT340-1



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A ₁	A ₂	А3	bp	С	D ⁽¹⁾	E ⁽¹⁾	e	HE	L	Lp	Q	٧	w	у	Z ⁽¹⁾	θ
mm	2.0	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	8.4 8.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	0.8 0.4	8° 0°

Note

1. Plastic or metal protrusions of 0.20 mm maximum per side are not included.

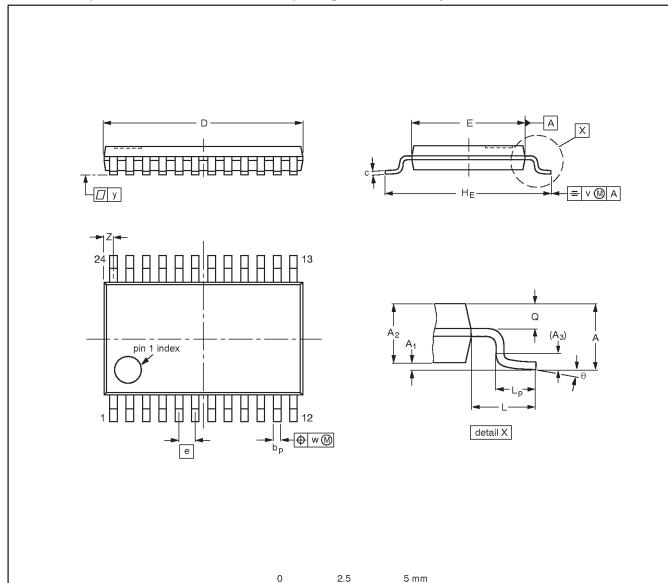
OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT340-1		MO-150				-95-02-04 99-12-27	

Octal transceiver with parity generator/checker (3-State)

74ABT833

TSSOP24: plastic thin shrink small outline package; 24 leads; body width 4.4 mm

SOT355-1



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A ₁	A ₂	А3	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Q	٧	w	у	Z ⁽¹⁾	θ
mm	1.10	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	7.9 7.7	4.5 4.3	0.65	6.6 6.2	1.0	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT355-1		MO-153				-95-02-04 99-12-27	

Octal transceiver with parity generator/checker (3-State)

74ABT833

REVISION HISTORY

Rev	Date	Description
_2	20021217	Product data (9397 750 10851); ECN 853-1619 29289 of 12 December 2002. Supersedes data of 21 June 1993.
		Modifications:
		Ordering information table: remove "North America" column; remove 74ABT833N package offering.
_1	19930621	Product specification. ECN 853-1619 10087 of 21 June 1993.

Octal transceiver with parity generator/checker (3-State)

74ABT833

Data sheet status

Level	Data sheet status ^[1]	Product status ^[2] [3]	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

^[1] Please consult the most recently issued data sheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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Document order number: 9397 750 10851

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^[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.

^[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.